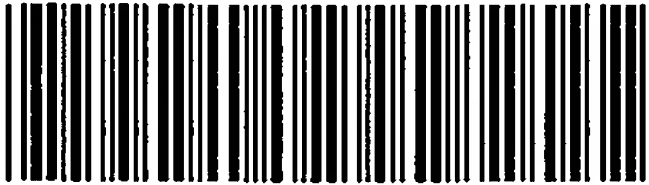


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/621,074	LAM ET AL.	
	Examiner	Art Unit	
	Sun J. Lin	2825	

SEARCHED			
Class	Subclass	Date	Examiner
716	1	2/22/2005	JSL
716	16	2/22/2005	JSL
716	17	2/22/2005	JSL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST [USPAT;US-PGPUB;UPO;JPO;DERWENT;IBM_T DB	2/22/2005	JSL
EAST [USPAT;US-PGPUB;UPO;JPO;DERWENT;IBM_T DB	6/30/2005	JSL
EAST [USPAT;US-PGPUB;UPO;JPO;DERWENT;IBM_T DB	7/11/2005	JSL
EAST [USPAT;US-PGPUB;UPO;JPO;DERWENT;IBM_T DB	7/20/2005	JSL
IEEE	6/30/2005	JSL
GOOGLE	7/11/2005	JSL